


<b>Search Notes</b> 	<b>Application/Control No.</b> 10595523	<b>Applicant(s)/Patent Under Reexamination</b> NAKAYAMA ET AL.
	<b>Examiner</b> JAE LEE	<b>Art Unit</b> 2823

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search: see attached search histories	07/10/2008	JML
continued EAST search	07/15/2008	JML
continued EAST search	06/02/2009	JML
continued EAST search	11/20/2009	JML
continued EAST search	10/27/2010	JML

INTERFERENCE SEARCH			
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